

## STL60N32N3LL

Dual N-channel 30 V, 0.005 Ω, 15 A PowerFLAT<sup>™</sup> 5x6 asymmetrical double island, STripFET<sup>™</sup> Power MOSFET

### **Features**

Order code		V <sub>DSS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub>
STL60N32N3LL	$Q_1$	30 V	< 0.0092 Ω	13.6 A
O I LOUINOZINOLL	$Q_2$	30 V	< 0.0055 Ω	15 A

- R<sub>DS(on)</sub> \* Q<sub>g</sub> industry benchmark
- Extremely low on-resistance R<sub>DS(on)</sub>
- Very low switching gate charge
- High avalanche ruggedness
- Low gate drive power losses

## Application

■ Switching applications

### **Description**

This device is a dual N-channel Power MOSFET which utilizes the latest generation of design rules for ST's proprietary STripFET™ V and STripFET™ VI DeepGATE™ technology. The lowest available RDS(on)\* Qg in this chip scale package renders the device suitable for the most demanding DC-DC converter applications, where high power density is required.

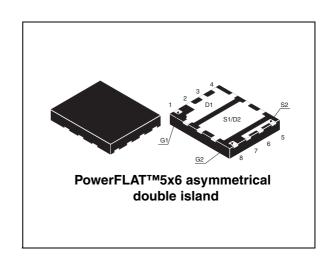


Figure 1. Internal schematic diagram

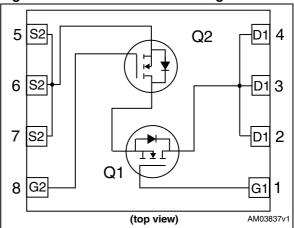


Table 1. Device summary

Order code	Marking	Package	Packaging
STL60N32N3LL	60N32N3LL	PowerFLAT™5x6 asymmetrical double island	Tape and reel

February 2012 Doc ID 17266 Rev 3 1/14

Contents STL60N32N3LL

### **Contents**

1	Elec	trical ra	itings		 	 3
2	Elec	trical ch	naracteristics		 	 4
	2.1	Electri	cal characteristics	s (curves).	 	 6
		2.1.1	Graphs for Q1		 	 6
		2.1.2	Graphs for Q2		 	 8
3	Test	circuits	s		 	 . 10
4	Pack	age me	echanical data		 	 . 11
5	Povi	eion hid	story			12

STL60N32N3LL Electrical ratings

## 1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Туре	Value	Unit
V <sub>DS</sub>	Drain-source voltage	Q <sub>1</sub> Q <sub>2</sub>	30 30	V V
V <sub>GS</sub>	Gate- source voltage	Q <sub>1</sub> Q <sub>2</sub>	± 20 ± 20	V V
I <sub>D</sub> <sup>(1)</sup>	Drain current (continuous) at T <sub>C</sub> = 25 °C	Q <sub>1</sub> Q <sub>2</sub>	32 60	A A
I <sub>D</sub> <sup>(1)</sup>	Drain current (continuous) at T <sub>C</sub> = 100 °C	Q <sub>1</sub> Q <sub>2</sub>	23 37	A A
I <sub>D</sub> <sup>(2)</sup>	Drain current (continuous) at T <sub>pcb</sub> = 25 °C	Q <sub>1</sub> Q <sub>2</sub>	13.6 15	A A
I <sub>D</sub> <sup>(2)</sup>	Drain current (continuous) at T <sub>pcb</sub> = 100 °C	Q <sub>1</sub> Q <sub>2</sub>	8.5 9.3	A A
I <sub>DM</sub> <sup>(2),(3)</sup>	Drain current (pulsed)	Q <sub>1</sub> Q <sub>2</sub>	54.4 60	A A
P <sub>TOT</sub> <sup>(1)</sup>	Total dissipation at T <sub>C</sub> = 25 °C	Q <sub>1</sub> Q <sub>2</sub>	23 50	W W
P <sub>TOT</sub> <sup>(2)</sup>	Total dissipation at T <sub>pcb</sub> = 25 °C	Q <sub>1</sub> Q <sub>2</sub>	3.12 3.12	W W
T <sub>j</sub>	Operating junction temperature		-55 to 150	°C
T <sub>stg</sub>	Storage temperature		-55 to 150	

<sup>1.</sup> This value is according  $toR_{thj-c}$ 

Table 3. Thermal data

Symbol	Parameter	Туре	Value	Unit
R <sub>thj-pcb</sub> <sup>(1)</sup>	Thermal resistance junction-pcb max		40	°C/W
R <sub>thj-c</sub>	Thermal resistance junction-case	Q <sub>1</sub> Q <sub>2</sub>	5.5 2.5	°C/W

<sup>1.</sup> When mounted on FR-4 board of 1inch², 2oz Cu, t < 10 sec

<sup>2.</sup> This value is according  $toR_{thi-pcb}$ 

<sup>3.</sup> Pulse width limited by safe operating area

Electrical characteristics STL60N32N3LL

## 2 Electrical characteristics

( $T_{CASE}$ =25°C unless otherwise specified)

Table 4. On/off states

Symbol	Parameter	Test conditions	Туре	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source Breakdown voltage	$I_D = 250 \ \mu A, \ V_{GS} = 0$	Q <sub>1</sub> Q <sub>2</sub>	30 30			V V
I <sub>DSS</sub>	Zero gate voltage Drain current (V <sub>GS</sub> = 0)	V <sub>DS</sub> = 30 V	Q <sub>1</sub> Q <sub>2</sub>			1	μ <b>Α</b> μ <b>Α</b>
I <sub>DSS</sub>	Zero gate voltage Drain current (V <sub>GS</sub> = 0)	V <sub>DS</sub> =30 V, T <sub>C</sub> =125°C	Q <sub>1</sub> Q <sub>2</sub>			10 10	μA μA
I <sub>GSS</sub>	Gate-body leakage current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ± 20 V	Q <sub>1</sub> Q <sub>2</sub>			±100 ±100	nA nA
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS},$ $I_D = 250 \mu A$	Q <sub>1</sub> Q <sub>2</sub>	1			V V
R <sub>DS(on)</sub>	Static drain-source on resistance	$V_{GS} = 10 \text{ V}, I_D = 6.8 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 7.5 \text{ A}$	Q <sub>1</sub> Q <sub>2</sub>		0.0085 0.005	0.0092 0.0055	Ω
R <sub>DS(on)</sub>	Static drain-source on resistance	$V_{GS} = 4.5 \text{ V}, I_D = 6.8 \text{ A}$ $V_{GS} = 4.5 \text{ V}, I_D = 7.5 \text{ A}$	Q <sub>1</sub> Q <sub>2</sub>		0.0109 0.0065	0.012 0.0073	Ω Ω

Table 5. Dynamic

Symbol	Parameter	Test conditions	Туре	Min.	Тур.	Max.	Unit
C <sub>iss</sub>	Input capacitance		Q <sub>1</sub> Q <sub>2</sub>	-	950 1690	-	pF pF
C <sub>oss</sub>	Output capacitance	$V_{DS} = 25 \text{ V, f} = 1 \text{ MHz,}$ $V_{GS} = 0$	Q <sub>1</sub> Q <sub>2</sub>	-	193 291	-	pF pF
C <sub>rss</sub>	Reverse transfer capacitance		Q <sub>1</sub> Q <sub>2</sub>	-	27.6 176	-	pF pF
Qg	Total gate charge	$V_{DD} = 15 \text{ V}, I_{D} = 15 \text{ A}, V_{GS} = 4.5 \text{ V}$ (see Figure 25)	Q <sub>1</sub> Q <sub>2</sub>	-	6.6 17	-	nC nC
$Q_{gs}$	Gate-source charge		Q <sub>1</sub> Q <sub>2</sub>	-	3.3 8	-	nC nC
$Q_{gd}$	Gate-drain charge		Q <sub>1</sub> Q <sub>2</sub>	-	2.4 6	-	nC nC

Table 6. Switching times

Symbol	Parameter	Test conditions	Туре	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub>	Turn-on delay time Rise time	$V_{DD}$ =15 V, $I_{D}$ =7.5 A, $R_{G}$ =4.7 $\Omega$ , $V_{GS}$ = 4.5 V (see Figure 29)	$\begin{array}{c} Q_1 \\ Q_2 \\ Q_1 \\ Q_2 \end{array}$	-	10.8 9.5 15.6 30	-	ns ns ns ns
t <sub>d(off)</sub>	Turn-off delay time Fall time	$V_{DD}$ =15 V, $I_{D}$ =7.5 A, $R_{G}$ =4.7 $\Omega$ , $V_{GS}$ = 4.5 V (see Figure 29)	$\begin{array}{c} Q_1 \\ Q_2 \\ Q_1 \\ Q_2 \end{array}$	-	14.2 37 6 12	-	ns ns ns ns

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Туре	Min.	Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain current	$V_{DD}$ =15 V, $I_{D}$ =7.5 A $R_{G}$ =4.7 $\Omega$ $V_{GS}$ =4.5 V	Q <sub>1</sub> Q <sub>2</sub>	-		13.6 15	A A
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current (pulsed)	$V_{DD}$ =15 V, $I_{D}$ = 7.5 A $R_{G}$ =4.7 $\Omega$ $V_{GS}$ =4.5 V	Q <sub>1</sub> Q <sub>2</sub>	-		54.4 60	A A
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	$I_{SD} = 15 \text{ A}, V_{GS} = 0$	Q <sub>1</sub> Q <sub>2</sub>	-		1.1 1.1	V V
t <sub>rr</sub>	Reverse recovery time Reverse recovery charge	$I_{SD} = 15 \text{ A},$ $V_{DD} = 15 \text{ V}$ $di/dt = 100 \text{ A/}\mu\text{s},$	Q <sub>1</sub> Q <sub>2</sub> Q <sub>1</sub> Q <sub>2</sub>	-	20 24 10 16.8		ns ns nC nC
I <sub>RRM</sub>	Reverse recovery current	$T_j = 150^{\circ}C$ (see Figure 29)	$Q_1$ $Q_2$		1 1.4		A A

<sup>1.</sup> Pulse width limited by safe operating area.

<sup>2.</sup> Pulsed: Pulse duration =  $300 \mu s$ , duty cycle 1.5%

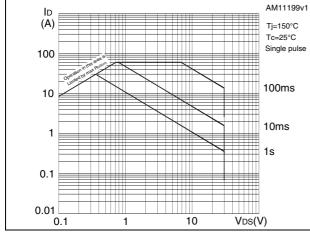
**Electrical characteristics** STL60N32N3LL

#### **Electrical characteristics (curves)** 2.1

#### 2.1.1 **Graphs for Q1**

Safe operating area Figure 2.

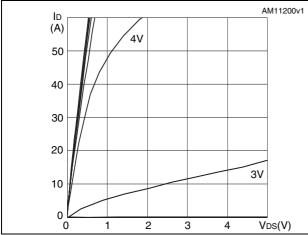
Figure 3. Thermal impedance PCB\_PowerFLAT 10° δ=0.5 0.2 10 0.02



10 10° 10<sup>-4</sup> 10° 10<sup>2</sup>  $t_p(s)$ 10<sup>-1</sup> 10<sup>1</sup>

Figure 4. **Output characteristics** 

Figure 5. **Transfer characteristics** 



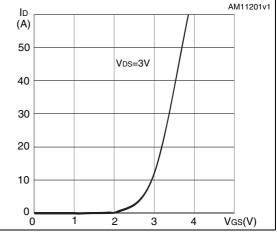
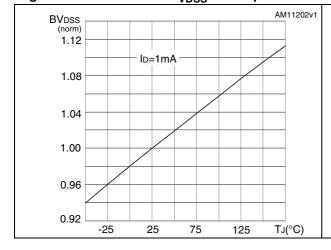
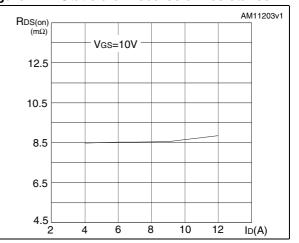


Figure 6. Normalized B<sub>VDSS</sub> vs temperature

Figure 7. Static drain-source on resistance





6/14 Doc ID 17266 Rev 3

AM11204v1 AM11205v1 Vgs С (pF) (V) 1410 VDD=15V 10 ID=13.6A 1210 8 1010 Ciss 6 810 610 4 410 2 210 Coss Crss 10 2 4 6 8 10 12 14 Qg(nC) 10 20 V<sub>DS</sub>(V)

Figure 8. Gate charge vs gate-source voltage Figure 9. Capacitance variations

Figure 10. Normalized gate threshold voltage Figure 11. Normalized on resistance vs vs temperature temperature

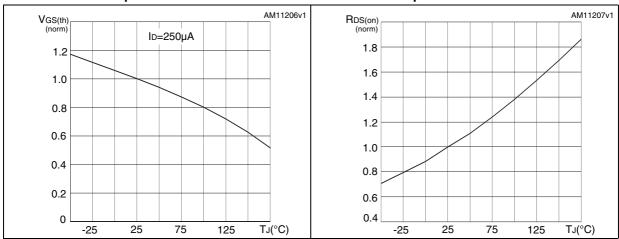
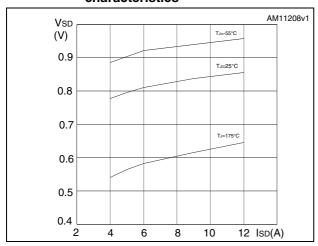


Figure 12. Source-drain diode forward characteristics

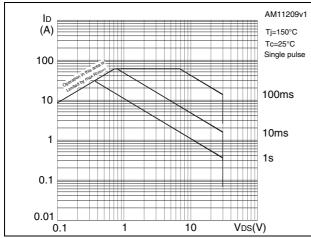


577

### 2.1.2 Graphs for Q2

Figure 13. Safe operating area

Figure 14. Thermal impedance



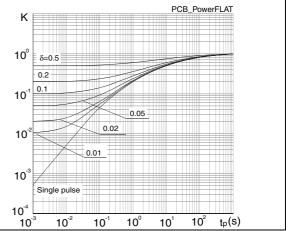
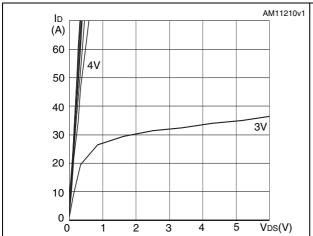


Figure 15. Output characteristics

Figure 16. Transfer characteristics



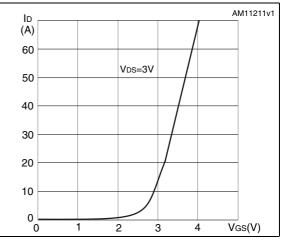
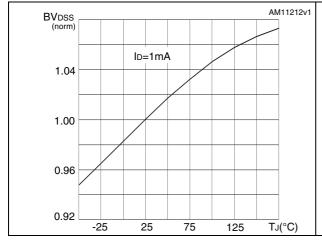
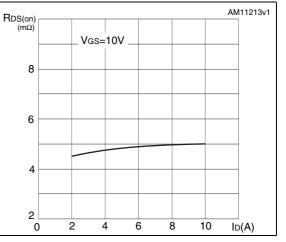


Figure 17. Normalized B<sub>VDSS</sub> vs temperature

Figure 18. Static drain-source on resistance





8/14 Doc ID 17266 Rev 3

AM11214v1 AM11215v1 Vgs С (V) (pF) VDD=15V 12 ID=15A 1600 10 Ciss 1100 8 6 600 4 100 2 Coss Crss VDS(V) 10 15 20 25 30 35 Qg(nC) ō 10 20

Figure 19. Gate charge vs gate-source voltage Figure 20. Capacitance variations

Figure 21. Normalized gate threshold voltage Figure 22. Normalized on resistance vs vs temperature temperature

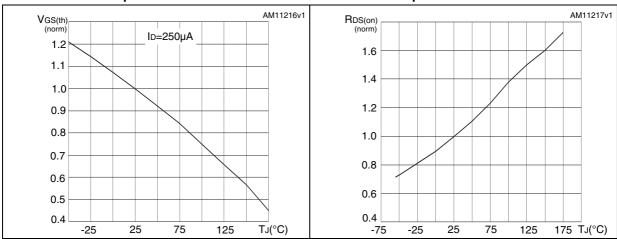
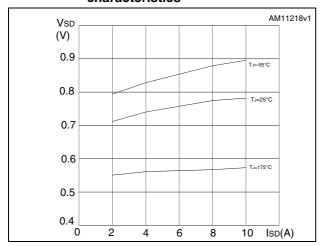


Figure 23. Source-drain diode forward characteristics



**577** 

Doc ID 17266 Rev 3

9/14

Test circuits STL60N32N3LL

### 3 Test circuits

Figure 24. Switching times test circuit for resistive load

Figure 25. Gate charge test circuit

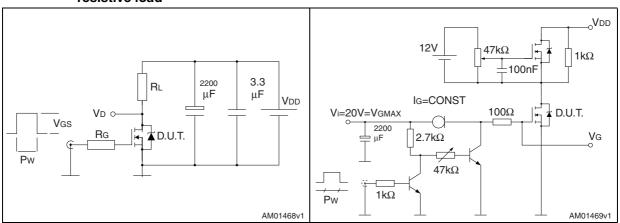


Figure 26. Test circuit for inductive load switching and diode recovery times

Figure 27. Unclamped inductive load test circuit

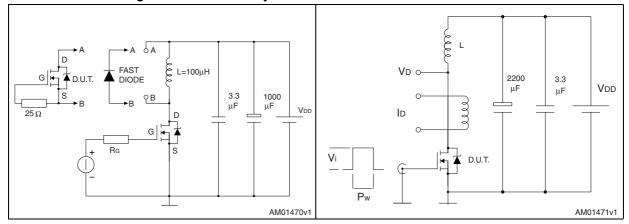
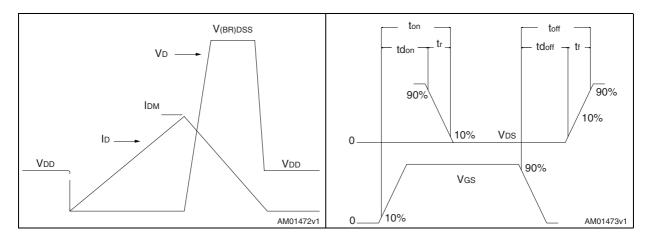


Figure 28. Unclamped inductive waveform

Figure 29. Switching time waveform



10/14 Doc ID 17266 Rev 3

577

### 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

Table 8. PowerFLAT™ 5x6 asymmetrical double island dimentions

Dim.	mm					
Dilli.	Min.	Тур.	Max.			
Α	0.80		1.00			
A1			0.05			
b	0.45		0.55			
D	4.90	5.00	5.10			
Е	5.90	6.00	6.10			
е		1.27				
L	0.40		0.60			
aaa		0.10				
bbb		0.10				
ccc		0.10				

Figure 30. Package drawing

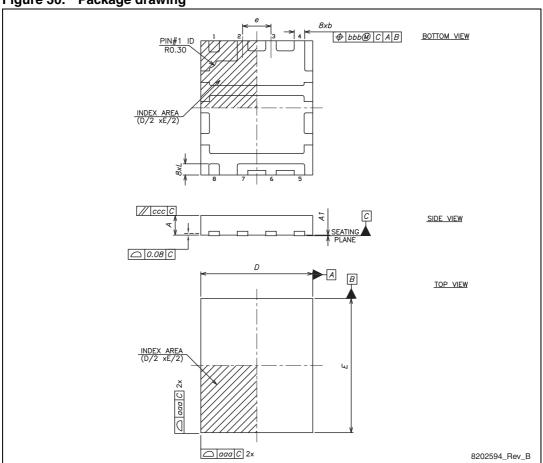
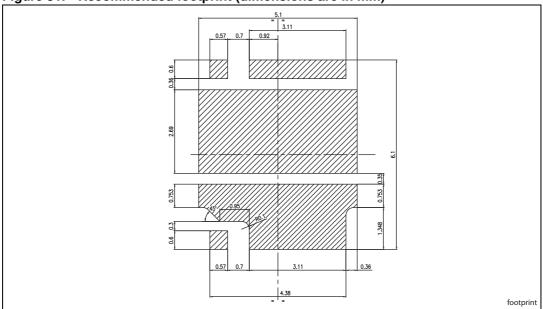


Figure 31. Recommended footprint (dimensions are in mm)



577

STL60N32N3LL Revision history

# 5 Revision history

Table 9. Document revision history

Date	Revision	Changes
15-Mar-2010	1	First release
07-Feb-2011	2	Document status promoted from target specification to preliminary data.
21-Feb-2012	3	Document status promoted from preliminary data to datasheet.  Section 2.1: Electrical characteristics (curves) has been added.  Section 4: Package mechanical data has been updated.  Minor text changes.

#### Please Read Carefully:

Information in this document is provided solely in connection with ST products. STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, modifications or improvements, to this document, and the products and services described herein at any time, without notice.

All ST products are sold pursuant to ST's terms and conditions of sale.

Purchasers are solely responsible for the choice, selection and use of the ST products and services described herein, and ST assumes no liability whatsoever relating to the choice, selection or use of the ST products and services described herein.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted under this document. If any part of this document refers to any third party products or services it shall not be deemed a license grant by ST for the use of such third party products or services, or any intellectual property contained therein or considered as a warranty covering the use in any manner whatsoever of such third party products or services or any intellectual property contained therein.

UNLESS OTHERWISE SET FORTH IN ST'S TERMS AND CONDITIONS OF SALE ST DISCLAIMS ANY EXPRESS OR IMPLIED WARRANTY WITH RESPECT TO THE USE AND/OR SALE OF ST PRODUCTS INCLUDING WITHOUT LIMITATION IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION), OR INFRINGEMENT OF ANY PATENT, COPYRIGHT OR OTHER INTELLECTUAL PROPERTY RIGHT.

UNLESS EXPRESSLY APPROVED IN WRITING BY TWO AUTHORIZED ST REPRESENTATIVES, ST PRODUCTS ARE NOT RECOMMENDED, AUTHORIZED OR WARRANTED FOR USE IN MILITARY, AIR CRAFT, SPACE, LIFE SAVING, OR LIFE SUSTAINING APPLICATIONS, NOR IN PRODUCTS OR SYSTEMS WHERE FAILURE OR MALFUNCTION MAY RESULT IN PERSONAL INJURY, DEATH, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE. ST PRODUCTS WHICH ARE NOT SPECIFIED AS "AUTOMOTIVE GRADE" MAY ONLY BE USED IN AUTOMOTIVE APPLICATIONS AT USER'S OWN RISK.

Resale of ST products with provisions different from the statements and/or technical features set forth in this document shall immediately void any warranty granted by ST for the ST product or service described herein and shall not create or extend in any manner whatsoever, any liability of ST.

ST and the ST logo are trademarks or registered trademarks of ST in various countries.

Information in this document supersedes and replaces all information previously supplied.

The ST logo is a registered trademark of STMicroelectronics. All other names are the property of their respective owners.

© 2012 STMicroelectronics - All rights reserved

STMicroelectronics group of companies

Australia - Belgium - Brazil - Canada - China - Czech Republic - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan - Malaysia - Malta - Morocco - Philippines - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States of America

www.st.com

14/14 Doc ID 17266 Rev 3

